TOSHIBA BIPOLAR LINEAR INTEGRATED CIRCUIT SILICON MONOLITHIC

TA1230Z

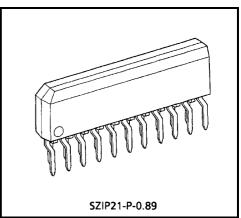
TV SOUND MULTIPLEX BROADCAST DEMODULATOR IC FOR EIAJ SYSTEM

The TA1230Z incorporates the functions required for EIAJ system TV sound multiplex broadcast demodulation and a trap for eliminating facsimile broadcast signals multiplexed in the sound multiplex broadcasting band. Automatic adjustment based on a 32 fH-oscillator makes adjustments other than separation unnecessary.

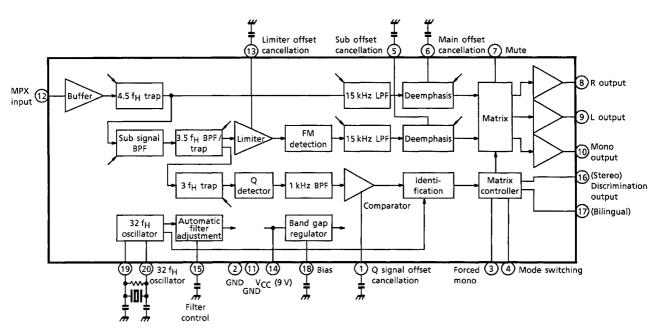
FEATURES

- Self-adjusting filter and discriminator circuit based on a 32 fH-oscillator
- Built-in trap eliminates facsimile broadcast signals

BLOCK DIAGRAM



Weight: 1.00 g (Typ.)



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The information contained herein is subject to change without notice.

PIN FUNCTIONS

PIN No.	PIN NAME	FUNCTION	INTERFACE CIRCUIT
1	Q signal offset cancellation	Cuts the DC component of the circuit shaping the waveform of the AM-detected cue signal. Connect a 0.1 μ F capacitor between this pin and GND. A 0.01 μ F capacitor may cause lower discrimination sensitivity because of the fluctuations in a capacitor of that rating.	
2	GND	—	—
3	Forced mono	Setting this pin to 5 V forcibly sets the mode to mono. This does not affect the discrimination output or bilingual broadcast decoding. As this is the PNP transistor input circuit, leaving the pin open sets the mode to forced mono. However, do not leave the pin open.	
4	Mode switching	The voltage of this pin is used to control the output state for bilingual broadcasting. 0 V : Main sound 2.5 V : Main / sub sound 5 V : Sub sound 9 V : Main / sub sound	
5	Sub offset elimination	Cuts the DC component of the sub sound signal processing section. Connect a 10 µF capacitor between this pin and GND.	
6	Main offset elimination	Cuts the DC component of the main-sound signal processing section. Connect a 10 μ F capacitor between this pin and GND.	

PIN No.	PIN NAME	FUNCTION	INTERFACE CIRCUIT
7	Mute	Setting this pin to 5V mutes all the outputs. Normally, fix to GND.	
8 9 10	R output L output Mono output	Output pins. A mono sound signal is output from pin 10 regardless of the state of pins 3 and 4 and the broadcasting mode. Set so that the maximum current output from these pins does not exceed 500 µA.	
11	GND	—	—
12	MPX input	Sound multiplex signal input pin. The input resistance is 10 k Ω (Typ.). The standard input level is 250 mV _{rms} (Equivalent to 100% modulation)	
13	Limiter offset elimination	Cuts the DC component of the sub-sound signal demodulation section. Connect a 0.01 μ F capacitor between this pin and GND.	
14	V _{CC}	The operating power supply voltage range is $9 \text{ V} \pm 10\%$.	_
15	Filter control	Used for the automatic filter adjustment circuit incorporated into the IC. Connect a 0.01 µF capacitor between this pin and GND.	
16 17	Stereo discrimination output Bilingual discrimination output	Broadcast mode discrimination output pins. This circuit is an open collector whose maximum sink current is 1 mA.	

PIN No.	PIN NAME FUNCTION		INTERFACE CIRCUIT
18	Bias	Eliminates IC internal bias noise. Connect a 10 μ F capacitor between this pin and GND.	
19 20	32 f _H oscillation	Ceramic oscillator connecting pins. TA1230Z uses this oscillation to automatically adjust the internal filter and to perform discrimination. Use a Murata CSB503E7 ceramic oscillator.	

ABSOLUTE RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Supply Voltage	V _{CC}	15	V
Power Dissipation	PD	890	mW
Operating Temperature	T _{opr}	-20~75	°C
Storage Temperature	T _{str}	-55~150	°C

Note: The power dissipation rating drops by 7.2 mW for every 1°C over 25°C.

OPERATING SUPPLY VOLTAGE

PIN No.	PIN NAME	MIN	TYP.	MAX	UNIT
14	V _{CC}	8.1	9.0	9.9	V

ELECTRICAL CHARACTERISTICS (Unless otherwise specified, V_{CC} = 9 V, Ta = 25°C) DC CHARACTERISTICS

CHARACTERISTIC	SYMBOL	TEST CIR- CUIT	TEST CONDITION	MIN	TYP.	MAX	UNIT
Current Dissipation	I _{CC}	_	—	28	34	42	mA
	V ₁	—	—	4.2	5.2	6.2	
	V ₅	—	—	3.5	4.5	5.5	
	V ₆	_	_	3.5	4.5	5.5	
	V ₈	_	_	2.1	3.1	4.1	
	V ₉	_	_	2.1	3.1	4.1	
Pin Voltage	V ₁₀	-	—	2.1	3.1	4.1	v
Pin voltage	V ₁₂	_	_	3.5	4.5	5.5	v
	V ₁₃	_	_	2.8	3.9	4.9	
	V ₁₅	_	_	2.5	4.5	6.5	
	V ₁₈	_	—	5.0	5.7	6.4	
	V ₁₉	_	—	3.5	4.5	5.5	
	V ₂₀	_	—	7.0	7.6	8.2	

AC CHARACTERISTICS

CHARA	SYMBOL	TEST CIR- CUIT	TEST CONDITION	MIN	TYP.	MAX	UNIT	
Output Level	V _{OUT}	_	(Note 1)	500	600	700	mV _{rms}	
Output Level Flu	ctuation	Δν _{ουτ}	_	(Note 2)	_	0.0	1.5	dB
Sub Output Leve	el Power Dependency	ΔVSUB	_	(Note 3)	—	0.0	0.5	dB
	Main Sound 100 Hz	A100 M	_		0.0	1.0	2.5	
Frequency	Main Sound 10 kHz	A10k M	_		-16	-13	-10	
Characteristics	Sub Sound 100 Hz	A100 S	_	(Note 4)	0.0	1.0	2.5	dB
	Sub Sound 10 kHz	A10k S	_		-16	-13	-10	
Total Harmonic	Main Sound	THD M	_	(Nieto E)	_	0.2	1.0	%
Distortion	Sub Sound	THD S	_	(Note 5)	_	0.7	1.0	70
S/N	Main Sound	S/NM	_	(Niete 6)	70	75		dB
5 / N	Sub Sound	S/NS	_	(Note 6)	60	65		uв
Carrier	Main Sound	VLeak M	_	(Note 7)	_	50	70	mVp-p
Leakage	Sub Sound	VLeak S	_	(Note 7)	_	50	70	шүр-р
Stereo Separatio	n	Sepa	_	(Note 8)	34	_	_	dB
Bilingual Crossta	lk	СТ	_	(Note 9)	60	_	_	dB
	Main (Max.)	Vmax M	_	(Note 10)	1.0	_	_	V
	Main / Sub (1) (Min.)	Vmin B (1)	_		_	_	1.2	
Bilingual Mode Switching	Main / Sub (1) (Max.)	Vmax B (1)	_		2.9	_		
Voltage	Sub (Min.)	Vmin S	-		—	_	4.2	
	Sub (Max.)	Vmax S	_		5.4	—		
	Main / Sub (2) (Min.)	Vmin B (2)	_		—	—	6.6	
Forced Mono	Off Voltage	Vmin FMono	Ι	(Note 11)	2.4	—		V
Voltage	On Voltage	Vmax FMono			—	-	2.6	v
Mute on Voltage		V Mute	-	(Note 12)	—	_	2.0	V
Mute Residual N	oise	V Mute	_	(Note 13)	—	—	1.5	mV _{p-p}
Mute DC Offset	L / R Output	V _{OS}	Ι	(Note 14)	—	5	100	mV
Voltage	M Output	v0s			_	_	300	1110
Sub Carrier Sens	sitivity	S _{SUB}	Ι	(Note 15)	_	-	12	dB
	No Modulation	SQo			8	_	_	
Cue Signal	L-R 900 Hz 100%	SQ900	_	(Note 16)	6	_	_	dB
Sensitivity	Sub Sound 1kHz 100%	SQ1k	—	(6	—	—	
Input Resistance		R _{IN}	_	(Note 17)	7	10	13	kΩ
Output Resistance	ce	R _{OUT}	—	(Note 18)	70	100	130	Ω

TEST CONDITIONS

	INPUT	MO	DE SETTI	NG	TEOT DU	
NOTE	SIGNAL	PIN 3	PIN 4	PIN 7	TEST PIN	TEST METHOD
1	Signal A	0 [V]	0 [V]	0 [V]	Pins 8, 9, 10	Measure the output level of each pin (V_OUT [mV _{rms}])
2	Signal A	0 [V]	0 [V]	0 [V]	Pins 8, 9	$ \begin{array}{l} \mbox{Calculate the output level ratio between pins 8 and 9 (V_8, V_9).} \\ \Delta V_{OUT} \ \mbox{[dB]} = 20 \cdot \ \mbox{\lambda og} \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \$
3	Signal B	0 [V]	5 [V]	0 [V]	Pins 8, 9	$ \begin{array}{l} \mbox{Raise V}_{CC} \mbox{ from 8.1V to 9.9 V and measure the output level} \\ (V_{V'}). \mbox{ Calculate the ratio against the output level } (V_{V}) \mbox{ when } \\ V_{CC} = 9V \\ \Delta V \mbox{Sub [dB]} = 20 \cdot \mbox{log } (V_{V'} / V_{V}) \end{array} $
4	Signal A Signal B Signal C Signal D	0 [V]	0 / 5 [V]	0 [V]	Pins 8, 9	$ \begin{array}{l} \label{eq:second} Set pin 4 to 0 \end{vsignal} A and measure the output level (V_{M1k}). Next, input signal C, D and measure its output level at 100 Hz and 10 kHz (V_{M100} and V_{M10k}). \\ A100 \end{vsignal} A 10 \end{vsignal} B 20 \end{vsignal} C 0 \end{vsignal} V_{M10k} \\ A10k \end{vsignal} M \end{vsignal} B 20 \end{vsignal} C \\ Set pin 4 to 5 \end{vsignal} V. Input signal B and measure the output level at 100 Hz and 10 \end{vsignal} C, D and measure its output level at 100 \end{vsignal} Hz \\ A100 \end{vsignal} B \\ A10k \end{vsignal} C \\ A100 \end{vsignal} C \\ A100 \end{vsignal} C \\ A100 \end{vsignal} C \\ A100 \end{vsignal} B \\ A100 \end{vsignal} C \\ A100 \end{vsignal} $
5	Signal A Signal B	0 [V]	0 / 5 [V]	0 [V]	Pins 8, 9	Set pin 4 to 0 V. Input signal A and measure the distortion factor (THD M [%]). Set pin 4 to 5 V. Input signal B and measure the distortion factor (THD S [%]).
6	Signal A Signal B Signal E	0 [V]	0 / 5 [V]	0 [V]	Pins 8, 9	$ \begin{array}{l} \label{eq:second} Set \mbox{ pin 4 to 0 V. Input signal B and measure the output level} \\ (S_M). \mbox{ Next, measure its output level (N_M) on no signal input condition.} \\ & S / N \mbox{ M [dB]} = 20 \mbox{ log } (S_M / \mbox{ N}_M) \\ Set \mbox{ pin 4 to 5 V. Input signal B and measure the output level (S_S). Next, input signal E and measure its output level (N_S).} \\ & S / N \mbox{ M [dB]} = 20 \mbox{ log } (S_S / \mbox{ N}_S) \\ \end{array} $
7	Signal E	0 [V]	0 / 5 [V]	0 [V]	Pins 8, 9	Set pin 4 to 0 V and set LPF output to through. Measure the output level (VLeak M). Set pin 4 to 5 V and set LPF output to through. Measure the output level (VLeak S).

NOTE	INPUT	MO	DE SETTI	ING										
NOTE	SIGNAL	PIN 3	PIN 4	PIN 7	TEST PIN	TEST METHOD								
8	Signal F	0 [V]	0 [V]	0 [V]	Pins 8, 9	Adjust the input signal amplitude so that the output level of pin 8 is at minimum. Measure the output levels of 1 kHz spectrum of pin 8 (V ₈) and pin 9 (V ₉) by a spectrum analyzer. Sepa [dB] = 20 log (V ₉ / V ₈)								
9	Signal H	0 [V]	2.5 [V]	0 [V]	Pins 8, 9	Measure the output levels of 1 kHz spectrum of pin 8 (V ₈) and pin 9 (V ₉) by a spectrum analyzer. CT [dB] = 20 log (V ₉ / V ₈)								
						Raise the voltage of pin 4 from 0 V. Measure the upper limit voltage (Vmax M [V]) holding the output from pin 8 at 1 kHz.								
						Reduce the voltage of pin 4 from 2.5 V. Measure the lower limit voltage (Vmin B (1) [V]) holding the output from pin 8 at 400 Hz.Raise the voltage of pin 4 from 2.5 V. Measure the upper limit voltage (Vmax B (1) [V]) holding the output from pin 9 at 1 kHz.								
10	Signal I	0 [V]	Variable	0 [V]	Pin 4	Reduce the voltage of pin 4 from 5 V. Measure the lower limit voltage (Vmin B (1) [V]) holding the output from pin 9 at 400Hz.								
						Reduce the voltage of pin 4 from 9 V. Measure the lower limit voltage (Vmin B (2) [V]) holding the output from pin 9 at 1 kHz.								
14	Oises al E	Mariakla	0.0.0	0.0.4		Raise the voltage of pin 3 from 0 V. Measure the upper limit voltage (Vmax FMono [V]) holding the output from pin 8 to 0 V.								
11	Signal E	E Variable	le 0 [V]	0 [V]	Pin 3	Reduce the voltage of pin 3 from 5 V. Measure the lower limit voltage (Vmin FMono [V]) holding the output from pin 8 at 1 kHz.								
12	Signal A	0 [V]	0 [V]	Variable	Pin 7	Raise the voltage of pin 7 from 0 V. Measure the voltage (Vmute [V]) when the output from pin 8 or pin 9 changes to 0 V.								
13	Signal A	0 [V]	0 [V]	5 [V]	Pins 8, 9, 10	Measure the output levels of the pins (VMute $[mV_{p-p}]$).								
14	No signal	0 [V]	0 [V]	0 / 5 [V]	Pins 8, 9, 10	Switch the pin 7 voltage between 0 V and 5 V. Measure the DC voltage change of the pins (V_OS [V]).								

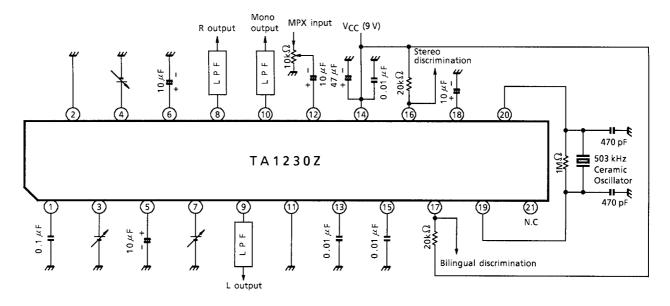
TEST CONDITIONS

NOTE	INPUT	MO	DE SETT	NG	TEST PIN	TEST METHOD
NOTE	SIGNAL	PIN 3	PIN 4	PIN 7	TEST PIN	TEST METHOD
15	Signal J	0 [V]	0 [V]	0 [V]	Pin 17	Input signal J. Lower the 31.47 [kHz] signal level from 150 [mV _{rms}]. Measure the 31.47 [kHz] signal level when the pin 17 voltage changes to 9 [V] (VSUB). S SUB = 20 łog (150 / VSUB) [dB]
16	Signal K Signal L Signal M	0 [V]	0 [V]	0 [V]	Pins 16, 17	Input signal K. Lower the cue signal level from 20 mV _{rms} . Measure the cue signal level when the pin 17 voltage changes to 9 V (V Qo [mV _{rms}]) S Qo [dB] = 20 log (20 / VQo) Input signal L. Lower the cue signal level from 20mV _{rms} . Measure the cue signal level when the pin 17 voltage changes to 9 V (VQ900 [mV _{rms}]) S Q900 [dB] = 20 log (20 / VQ900). Input signal M. Lower the cue signal level from 20 [mV _{rms}]. Measure the cue signal level when the pin 16 voltage changes to 9 V (VQ1k [mV _{rms}]) S Q1k [dB] = 20 log (20 / VQ1k).
17	Signal A	0 [V]	0 [V]	0 [V]	Pin 12	Measure the input resistance.
18	Signal A	0 [V]	0 [V]	0 [V]	Pins 8, 9, 10	Measure the output resistance.

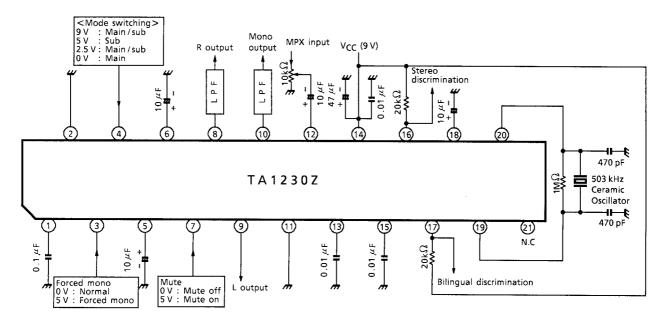
INPUT SIGNAL TABLE

		SUB S	SIGNAL	CUE SIGNAL		
SIGNAL	MAIN SIGNAL	CARRIER	MODULATION	CARRIER	MODULATION	
Signal A	1 kHz, 250 mV _{rms}	No signal	_	No signal	—	
Signal B	No signal	31.47 kHz, 150 mV _{rms}	1 kHz, 100% FM	55.07 kHz, 20 mV _{rms}	922.5 Hz, 60%AM	
Signal C	100Hz, 250 mV _{rms}	31.47 kHz, 150 mV _{rms}	100Hz, 100% FM	55.07 kHz, 20 mV _{rms}	922.5 Hz, 60%AM	
Signal D	10 kHz, 250 mV _{rms}	31.47 kHz, 150 mV _{rms}	10 kHz, 100% FM	55.07 kHz, 20 mV _{rms}	922.5 Hz, 60%AM	
Signal E	No signal	31.47 kHz, 150 mV _{rms}	No signal	55.07 kHz, 20 mV _{rms}	922.5 Hz, 60%AM	
Signal F	1 kHz, 125 mV _{rms}	31.47 kHz, 200 mV _{rms}	1 kHz (In-phase), 50% FM	55.07 kHz, 20 mV _{rms}	982.5 Hz, 60%AM	
Signal G	1 kHz, 250 mV _{rms}	31.47 kHz, 150 mV _{rms}	No signal	55.07 kHz, 20 mV _{rms}	922.5 Hz, 60%AM	
Signal H	1 kHz, 250 mV _{rms}	31.47 kHz, 150 mV _{rms}	1 kHz, 100% FM	55.07 kHz, 20 mV _{rms}	922.5 Hz, 60%AM	
Signal I	1 kHz, 250 mV _{rms}	31.47 kHz, 150 mV _{rms}	400Hz, 100% FM	55.07 kHz, 20 mV _{rms}	922.5 Hz, 60%AM	
Signal J	No signal	31.47 kHz, Variable	No signal	55.07 kHz, 20 mV _{rms}	922.5 Hz, 60%AM	
Signal K	No signal	31.47 kHz, 150 mV _{rms}	No signal	55.07 kHz, Variable	922.5 Hz, 60%AM	
Signal L	No signal	31.47 kHz, 200 mV _{rms}	900Hz, 100% FM	55.07 kHz, Variable	982.5 Hz, 60%AM	
Signal M	No signal	31.47 kHz, 150 mV _{rms}	1 kHz, 100% FM	55.07 kHz, Variable	922.5 Hz, 60%AM	

TEST CIRCUIT



LFP: 4-stage Butterworth, cutoff frequency 15 kHz



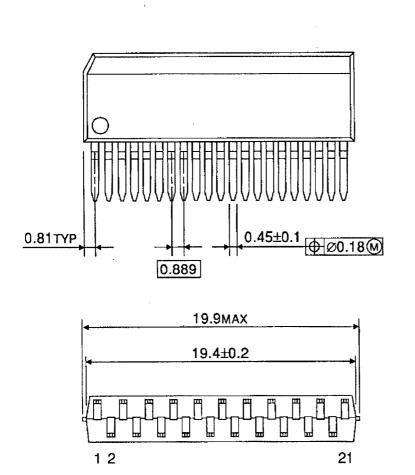
APPLICATION CIRCUIT

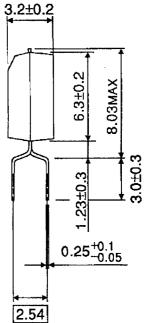
Ceramic oscillator : CSB503E7 (Murata)

PACKAGE DIMENSIONS

SZIP21-P-0.89

Unit : mm





Weight: 1.00g (Typ.)